

Notice of References Cited	Application/Control No. 10/696,817		Applicant(s)/Patent Under Reexamination LE, HIEN K.	
	Examiner Satish S. Rampuria		Art Unit 2191	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2006/0235732 A1	10-2006	Miller et al.	705/007
*	B	US-2006/0206246 A1	09-2006	Walker, Richard Clark	701/016
*	C	US-6,615,166 B1	09-2003	Guheen et al.	703/27
*	D	US-2003/0187676 A1	10-2003	Hack et al.	705/1
*	E	US-2003/0144969 A1	07-2003	Coyne, Patrick J.	705/400
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)			
	U	Sang Hun Oh et al., Software Quality Manager: a knowledge-based management tool of software metrics, IEEE, Aug 1994 Page(s): 796-800 vol.2			
	V	Ogasawara et al., Experiences of software quality management using metrics through the life-cycle, IEEE, Mar 1996 Page(s): 179-188			
	W	Suryan et al., Software product quality practices - quality measurement and evaluation using TL9000 and ISO/IEC 9126, IEEE, Oct. 2002 Page(s): 156- 160			
	X				

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.